



1741

P/2292-45 DIV

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of
Seok-Keun KOH, et al.
Serial No.: 09/887,189
Filed: June 22, 2001

New York, New York
Date: December 3, 2002
Group Art Unit: 1741
Examiner: Not Yet Assigned

For: PLASMA POLYMERIZATION ON SURFACE OF MATERIAL

Hon. Commissioner of Patents and Trademarks
Washington, D.C. 20231

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Sir:

Submitted herewith is a copy of art together with a form listing the same for the convenience of the Examiner.

I certify that each item of information contained in this Submission was cited in a communication from a foreign patent office in a counterpart foreign application not more than 3 months prior to the filing of this Submission.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner of Patents and Trademarks, Washington, D.C. 20231, on December 3, 2002

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December 3, 2002
Date of Signature

MM:cg
Enclosures

APPLICANT/ART CITATION (Use several sheets if necessary)							Application 09/887,189	OFGS File No. P/2292-45 DIV				
							Applicant Seok-Keun KOH, et al.					
							Filing Date June 22, 2001	Group Art Unit 1741				
U.S. PATENT DOCUMENTS												
Examiner Initial	Document Number						Date	Name	Class	Sub-class	Filing Date If Appropriate	
FOREIGN PATENT DOCUMENTS										Translation		
	Document Number						Date	Country	Class	Sub-class	Yes	No
JP	51	7	9	0	3	4	07/20/93	Japan				X
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)												
		English translation of Abstract for Japanese Patent No. JP 5-179034 dated 07/20/93										
Examiner							Date Considered					
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